N-channel TrenchMOS intermediate level FET Rev. 1 — 18 August 2010

Product data sheet

#### **Product profile** 1.

### 1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

### 1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources

### **1.3 Applications**

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

### 1.4 Quick reference data

#### Table 1 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

QUICK reference	uata					
Parameter	Conditions		Min	Тур	Max	Unit
drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	120	A
total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	306	W
Static characteristics						
drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>		-	1.6	1.9	mΩ
	Parameter         drain-source         voltage         drain current         total power         dissipation         tracteristics         drain-source         on-state	$\begin{array}{ll} \text{drain-source} & T_j \geq 25 \ ^\circ\text{C}; \ T_j \leq 175 \ ^\circ\text{C} \\ \text{voltage} & \text{drain current} & V_{\text{GS}} = 10 \ \text{V}; \ T_{\text{mb}} = 25 \ ^\circ\text{C}; \\ \text{see} \ \overline{\text{Figure 1}} & \text{total power} \\ \text{dissipation} & T_{\text{mb}} = 25 \ ^\circ\text{C}; \ \text{see} \ \overline{\text{Figure 2}} & \text{drain-source} \\ \hline \text{drain-source} & V_{\text{GS}} = 10 \ \text{V}; \ \text{I}_{\text{D}} = 25 \ \text{A}; \\ \text{on-state} & T_j = 25 \ ^\circ\text{C}; \ \text{see} \ \overline{\text{Figure 11}} & \text{drain-source} \\ \end{array}$	ParameterConditionsdrain-source voltage $T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$ drain current $V_{GS} = 10 \text{ V}; T_{mb} = 25 \text{ °C};$ total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 2total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 2total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 1total power dissipation $T_{mb} = 25 \text{ °C};$ see Figure 1	ParameterConditionsMindrain-source voltage $T_j \ge 25 \ ^{\circ}C; \ T_j \le 175 \ ^{\circ}C$ -drain current $V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C;$ [1]-total power dissipation $T_{mb} = 25 \ ^{\circ}C;$ see Figure 2-total power dissipation $T_{mb} = 25 \ ^{\circ}C;$ see Figure 2-tracteristics $T_{j} \ge 25 \ ^{\circ}C;$ see Figure 11-	ParameterConditionsMinTypdrain-source voltage $T_j \ge 25 \ ^\circ\C; \ T_j \le 175 \ ^\circ\C$ drain current $V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^\circ\C;$ [1]total power dissipation $T_{mb} = 25 \ ^\circ\C;$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\C;$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\C;$ see Figure 2total power dissipation $T_{mb} = 25 \ ^\circ\C;$ see Figure 1-1.6	ParameterConditionsMinTypMaxdrain-source voltage $T_j \ge 25 ^\circ\text{C};  T_j \le 175 ^\circ\text{C}$ 40drain current $V_{GS} = 10 ^\circ\text{V};  T_{mb} = 25 ^\circ\text{C};$ [1]120drain current $V_{GS} = 10 ^\circ\text{V};  T_{mb} = 25 ^\circ\text{C};$ [1]306total power dissipation $T_{mb} = 25 ^\circ\text{C};$ see Figure 2306tracteristicsdrain-source $T_j = 25 ^\circ\text{C};$ see Figure 11-1.61.9



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Table 1.	Quick reference da	tacontinued				
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Avalanche ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 120 \text{ A};  \text{V}_{\text{sup}} \leq 40 \text{ V}; \\ R_{\text{GS}} &= 50  \Omega;  \text{V}_{\text{GS}} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^{\circ}\text{C}; \text{ unclamped} \end{split} $	-	-	1.02	J
Dynamic characteristics						
Q <sub>GD</sub>	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure } 13}{\text{Figure } 14};$ $\text{see } \frac{\text{Figure } 14}{\text{Figure } 14}$	-	72	-	nC

[1] Continuous current is limited by package.

### 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		5
2	D	Drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

### 3. Ordering information

Table 3.         Ordering information						
Type number	Package					
	Name	Description	Version			
BUK661R9-40C	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404			

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### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>GS</sub>	gate-source voltage	Pulsed	<u>[1]</u>	-20	20	V
		DC	[2]	-16	16	V
I <sub>D</sub>	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{10000000000000000000000000000000000$	[3]	-	120	А
		$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see Figure 1	[3]	-	120	А
I <sub>DM</sub>	peak drain current	$T_{mb} = 25 \text{ °C}; t_p \le 10 \mu\text{s}; \text{ pulsed};$ see Figure 3		-	1107	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	306	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drai	n diode					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C	<u>[3]</u>	-	120	А
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	1107	А
Avalanche r	ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\label{eq:ld} \begin{array}{l} I_{D} = 120 \; A; \; V_{sup} \leq 40 \; V; \; R_{GS} = 50 \; \Omega; \\ V_{GS} = 10 \; V; \; T_{j(init)} = 25 \; ^{\circ}C; \; unclamped \end{array}$		-	1.02	J
E <sub>DS(AL)R</sub>	repetitive drain-source avalanche energy		[4][5][6]	-	-	J

[1] Accumulated pulse duration not to exceed 5mins.

[2] -16V accumulated duration not to exceed 168 hrs

[3] Continuous current is limited by package.

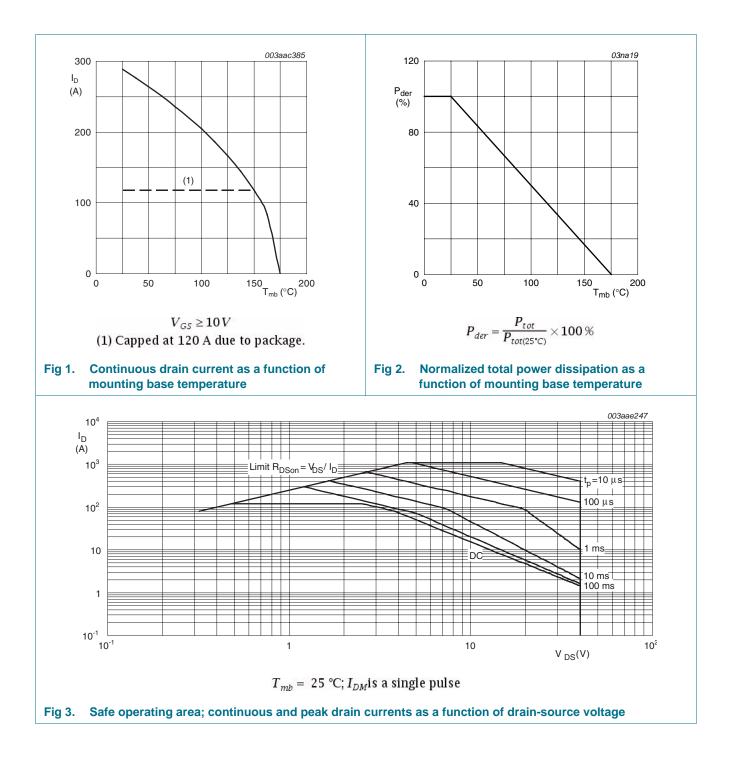
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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### 5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	see Figure 4	-	-	0.49	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W

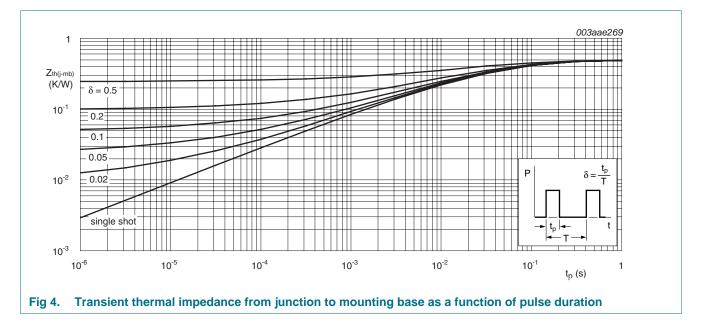


 Table 5.
 Thermal characteris

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### 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	40	-	-	V
	breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 10</u>	-	-	3.3	V
		I <sub>D</sub> = 2.5 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; see <u>Figure 10</u>	0.8	-	-	V
I <sub>DSS</sub>	drain leakage current	V <sub>DS</sub> = 40 V; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 175 °C	-	-	500	μA
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V};  V_{GS} = 20 \text{ V};  T_{j} = 25 ^{\circ}\text{C}$	-	2	100	nA
		$V_{DS} = 0 \text{ V}; \text{ V}_{GS} = -20 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	1.6	1.9	mΩ
		V <sub>GS</sub> = 5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	2	2.6	mΩ
		V <sub>GS</sub> = 4.5 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	-	2.25	3.1	mΩ
		$V_{GS}$ = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	4	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see <u>Figure 13</u> ; see <u>Figure 14</u>	-	260	-	nC
		$I_D = 25 A$ ; $V_{DS} = 32 V$ ; $V_{GS} = 5 V$ ; see <u>Figure 13</u> ; see <u>Figure 14</u>	-	147	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	38	-	nC
ସ୍ <sub>GD</sub>	gate-drain charge	see Figure 13; see Figure 14	-	72	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	11.3	15.1	nF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 16}{16}$	-	1447	1750	pF
C <sub>rss</sub>	reverse transfer capacitance		-	1014	1390	pF
d(on)	turn-on delay time	$V_{DS}$ = 30 V; $R_L$ = 1.2 $\Omega$ ; $V_{GS}$ = 10 V;	-	60	-	ns
r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	140	-	ns
d(off)	turn-off delay time		-	234	-	ns
t <sub>f</sub>	fall time		-	416	-	ns
L <sub>D</sub>	internal drain inductance	from upper edge of drain mounting base to centre of die; T <sub>j</sub> = 25 °C	-	3.5	-	nH
L <sub>S</sub>	internal source inductance	from source lead to source bond pad; $T_i = 25 ^{\circ}\text{C}$	-	7.5	-	nH

Symbol

Source-drain diode

# BUK661R9-40C

Max

Unit

Тур

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Min

V <sub>SD</sub>	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C};$ see <u>Figure 15</u>	-	0.8	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S} = 20 \text{ A}; dI_{S}/dt = -100 \text{ A}/\mu s; V_{GS} = 0 \text{ V};$	-	63	-	ns
Qr	recovered charge	V <sub>DS</sub> = 25 V	-	127	-	nC
250 9 <sub>fs</sub> (S) 200		003aae251 8 R <sub>DSon</sub> (mΩ) 6			003aae250	
150		4				
100 - 50 -		2				
o	20 40 60	80 <sub>I<sub>D</sub>(A)</sub> 100 0 0	5 10	15	20 V <sub>GS</sub> (V)	
	$T_j = 25 ^{\circ}C; V_{DS} = 10$ rward transconductance and current; typical values	as a function of Fig 6. Drain-sou	$T_j = 25 ^{\circ}C; I_D$ since on-state repurce voltage;	esistanc		unction
100 I <sub>D</sub> (A) 80 60		003aae248 80 3.6- (A) 60				
40		3.3 40 40				
20		20	T <sub>j</sub> = 175	°c/ / T	- j = 25 °C	
0 0	0.2 0.4 0.6	0.8 V <sub>DS</sub> (V) <sup>1</sup> 0 0	1 2		V <sub>GS</sub> (V) <sup>4</sup>	
Fig 7. Ou	$T_j = 25 ^{\circ}C$ Itput characteristics: drai	n current as a Fig 8. Transfer o	$V_{DS} > I_D \times R$		current	as a
		age; typical values function o				

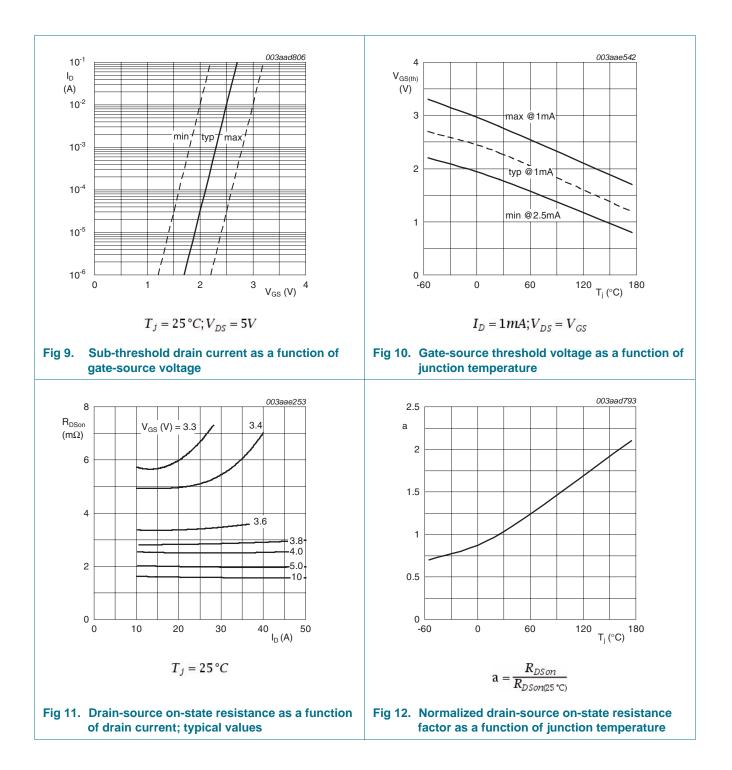
#### Table 6. Characteristics ...continued

Parameter

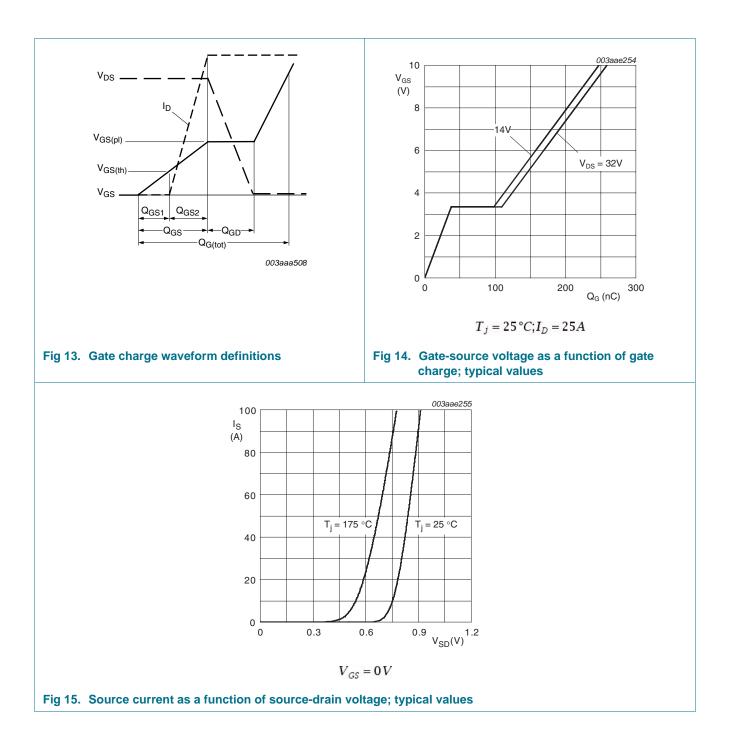
Conditions

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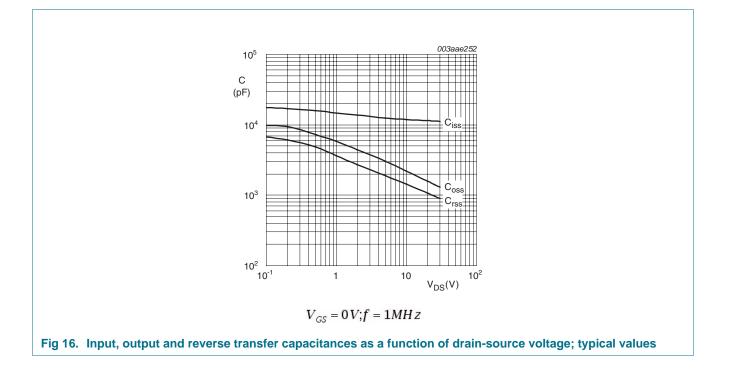


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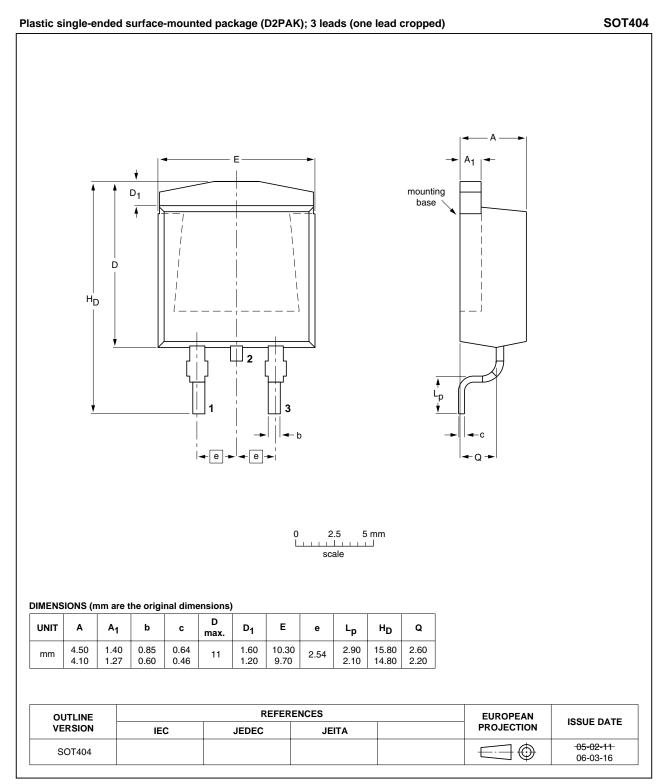
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### 7. Package outline



#### Fig 17. Package outline SOT404 (D2PAK)

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### N-channel TrenchMOS intermediate level FET

### 8. Revision history

Table 7. Revision h	Revision history						
Document ID	Release date	Data sheet status	Change notice	Supersedes			
BUK661R9-40C v.1	20100818	Product data sheet	-	-			

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#### Legal information 9.

#### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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